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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/626,543  
Applicant : Hirofumi HIRAYAMA  
Filed : July 25, 2003  
TC/A.U. : 3742  
Examiner : Mark H. Paschall

Docket No. : 1137-836  
Customer No. : 06449  
Confirmation No. : 1162

**SUPPLEMENTAL**  
**INFORMATION DISCLOSURE STATEMENT**

Director of the United States Patent  
and Trademark Office  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98,  
Applicant submits herewith information that the Office may wish  
to consider in examination of the subject application. Materials  
submitted for consideration are listed on the attached form PTO-  
1449.

I hereby certify that each item of information contained in  
this information disclosure statement was first cited in a  
communication from a foreign patent office in a counterpart  
foreign application not more than three months prior to the  
filing of this statement.

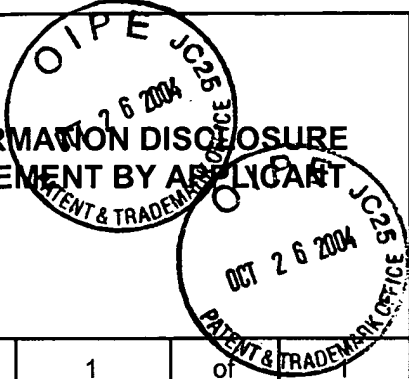
Respectfully submitted,

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 <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>			<i>Complete if Known</i>	
			Application Number	10/626,543
			Filing Date	July 25, 2003
			First Named Inventor	Hirofumi HIROYAMA
			Group Art Unit	3742
			Examiner Name	Mark H. Paschall
Sheet	1	of	Attorney Docket Number	1137-836

### U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code <sup>2</sup> (if known)		

### FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T <sup>6</sup>
		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
		JP	2-253316	A	OMRON TATEISI ELECTRON CO.	10-12-1990	Ab
		JP	5-25502	U		04-02-1993	Cim
		JP	11-345002	A	HITACHI LTD.; HITACHI ENG. CO. LTD.	12-14-1999	Ab

Examiner Signature		Date Considered	
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code.

<sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind